

Surface Analysis Solutions

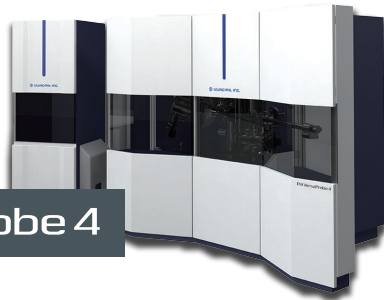


Scanning XPS Microprobe

New

The latest generation of PHI's Multi-technique XPS

- High-Sensitivity Analysis from Micro to Large Areas
- The Ultimate in Depth Profiling
- Unique and Automated Charge Neutralization
- A Wide Selection of Options



PHI VersaProbe 4



Time-of-Flight SIMS

New

PHI's latest generation TOF-SIMS

- Primary Ion Gun for High-Precision Measurements
- Triple Focusing Electrostatic Analyzer for Complex Sample Geometries
- Automated Multi-sample Exchange in TOF-SIMS
- Molecular Structure Analysis based on Parallel Imaging MS/MS
- A Wide Selection of Options



PHI nanoTOF 3



Dual Scanning XPS

Laboratory XPS/HAXPES analysis Chemical state analysis with > 10 nm

- Monochromated Dual X-ray Source: Cr K α 5.4 keV and Al K α 1.5 keV
- Quantitative Analysis by HAXPES
- Same Analysis Position for Cr K α and Al K α X-ray
- Automated Dual Beam Charge Neutralization



PHI Quantes



Scanning AES

Nanometer-level analysis Highly sensitive nano analysis

- High Sensitivity/High Throughput Analysis with Coaxial Cylindrical Mirror Analyzer (CMA)
- SEM Resolution \leq 3 nm, AES Resolution \leq 8 nm
- High Energy Resolution Auger Map



PHI 710

